- **Member of the Texas Instruments *Widebus*™ Family**
- ***EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process**
- **Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 250 mA Per JEDEC Standard JESD-17**
- **Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors**
- **Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages**

**DGG OR DL PACKAGE
(TOP VIEW)**

1$\overline{\text{OE1}}$	1	56	1$\overline{\text{OE2}}$
1Y1	2	55	1A1
1Y2	3	54	1A2
GND	4	53	GND
1Y3	5	52	1A3
1Y4	6	51	1A4
V_{CC}	7	50	V_{CC}
1Y5	8	49	1A5
1Y6	9	48	1A6
1Y7	10	47	1A7
GND	11	46	GND
1Y8	12	45	1A8
1Y9	13	44	1A9
1Y10	14	43	1A10
2Y1	15	42	2A1
2Y2	16	41	2A2
2Y3	17	40	2A3
GND	18	39	GND
2Y4	19	38	2A4
2Y5	20	37	2A5
2Y6	21	36	2A6
V_{CC}	22	35	V_{CC}
2Y7	23	34	2A7
2Y8	24	33	2A8
GND	25	32	GND
2Y9	26	31	2A9
2Y10	27	30	2A10
2$\overline{\text{OE1}}$	28	29	2$\overline{\text{OE2}}$

description

This 20-bit noninverting buffer/driver is designed for 2.3-V to 3.6-V V_{CC} operation.

The SN74ALVCH162827 is composed of two 10-bit sections with separate output-enable signals. For either 10-bit buffer section, the two output-enable (1$\overline{\text{OE1}}$ and 1$\overline{\text{OE2}}$ or 2$\overline{\text{OE1}}$ and 2$\overline{\text{OE2}}$) inputs must both be low for the corresponding Y outputs to be active. If either output-enable input is high, the outputs of that 10-bit buffer section are in the high-impedance state.

The outputs, which are designed to sink up to 12 mA, include 26-Ω resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down, $\overline{\text{OE}}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH162827 is available in TI’s shrink small-outline (DL) and thin shrink small-outline (DGG) packages, which provide twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN74ALVCH162827 is characterized for operation from –40°C to 85°C.

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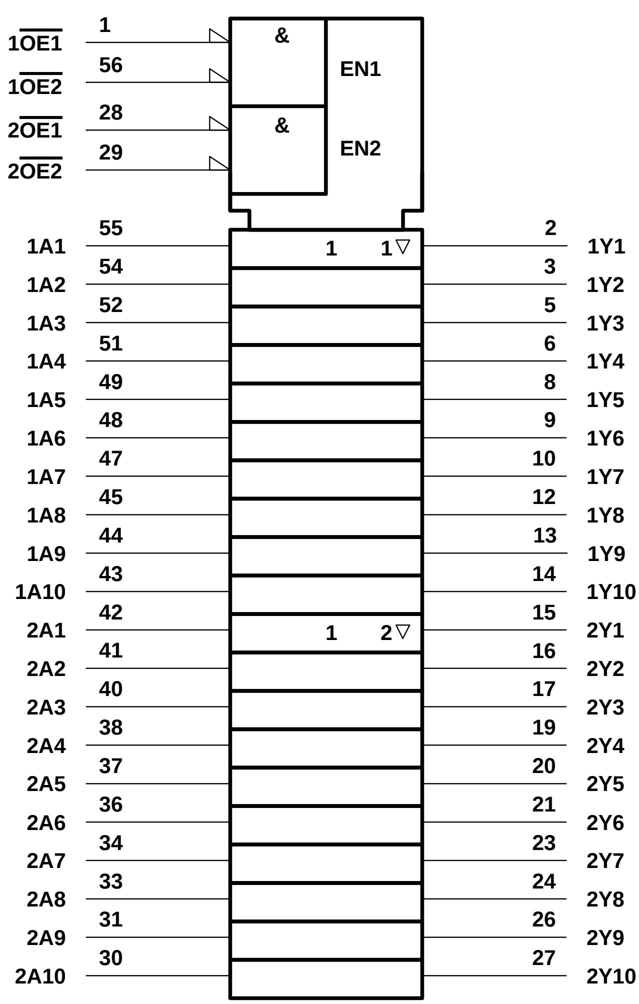
FUNCTION TABLE
(each 10-bit section)

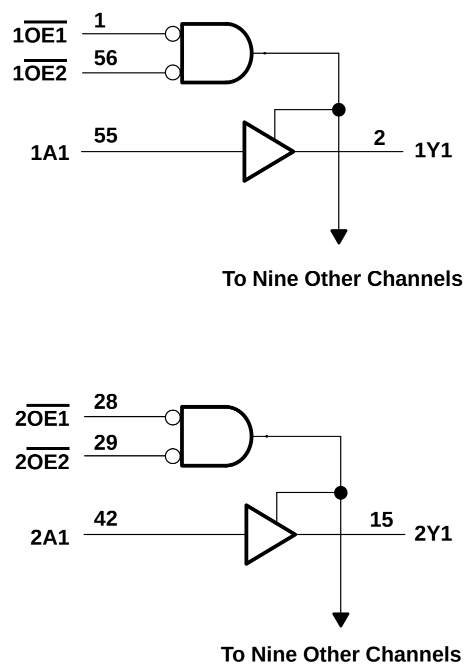
INPUTS			OUTPUT
$\overline{OE1}$	$\overline{OE2}$	A	Y
L	L	L	L
L	L	H	H
H	X	X	Z
X	H	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . –0.5 V to 4.6 V
Input voltage range, V_I (see Note 1) . . . . –0.5 V to 4.6 V
Output voltage range, V_O (see Notes 1 and 2) . . . . –0.5 V to V_{CC} + 0.5 V
Input clamp current, I_{IK} (V_I < 0) . . . . –50 mA
Output clamp current, I_{OK} (V_O < 0 or V_O > V_{CC}) . . . . ±50 mA
Continuous output current, I_O (V_O = 0 to V_{CC}) . . . . ±50 mA
Continuous current through each V_{CC} or GND . . . . ±100 mA
Maximum power dissipation at T_A = 55°C (in still air): DGG package . . . . 1 W
DL package . . . . 1.4 W
Storage temperature range, T_{stg} . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the 1994 *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002B.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
V_{CC}	Supply voltage		2.3	3.6	V
V_{IH}	High-level input voltage	V_{CC} = 2.3 V to 2.7 V	1.7		V
		V_{CC} = 2.7 V to 3.6 V	2		
V_{IL}	Low-level input voltage	V_{CC} = 2.3 V to 2.7 V		0.7	V
		V_{CC} = 2.7 V to 3.6 V		0.8	
V_I	Input voltage		0	V_{CC}	V
V_O	Output voltage		0	V_{CC}	V
I_{OH}	High-level output current	V_{CC} = 2.3 V		–6	mA
		V_{CC} = 2.7 V		–8	
		V_{CC} = 3 V		–12	
I_{OL}	Low-level output current	V_{CC} = 2.3 V		6	mA
		V_{CC} = 2.7 V		8	
		V_{CC} = 3 V		12	
Δt/Δv	Input transition rise or fall rate		0	10	ns/V
T_A	Operating free-air temperature		–40	85	°C

NOTE 4: Unused control inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		V_{CC}†	MIN	TYP‡	MAX	UNIT
V_{OH}		I_{OH} = –100 µA		MIN to MAX	V_{CC}–0.2			V
		I_{OH} = –4 mA,	V_{IH} = 1.7 V	2.3 V	1.9			
		I_{OH} = –6 mA	V_{IH} = 1.7 V	2.3 V	1.7			
			V_{IH} = 2 V	3 V	2.4			
		I_{OH} = –8 mA,	V_{IH} = 2 V	2.7 V	2			
		I_{OH} = –12 mA,	V_{IH} = 2 V	3 V	2			
V_{OL}		I_{OL} = 100 µA		MIN to MAX			0.2	V
		I_{OL} = 4 mA,	V_{IL} = 0.7 V	2.3 V			0.4	
		I_{OL} = 6 mA	V_{IL} = 0.7 V	2.3 V			0.55	
			V_{IL} = 0.8 V	3 V			0.55	
		I_{OL} = 8 mA,	V_{IL} = 0.8 V	2.7 V			0.6	
		I_{OL} = 12 mA,	V_{IL} = 0.8 V	3 V			0.8	
I_I		V_I = V_{CC} or GND		3.6 V			±5	µA
$I_{I(hold)}$		V_I = 0.7 V		2.3 V	45			µA
		V_I = 1.7 V			–45			
		V_I = 0.8 V		3 V	75			
		V_I = 2 V			–75			
		V_I = 0 to 3.6 V		3.6 V			±500	
I_{OZ}		V_O = V_{CC} or GND		3.6 V			±10	µA
I_{CC}		V_I = V_{CC} or GND,	I_O = 0	3.6 V			40	µA
ΔI_{CC}		One input at V_{CC} – 0.6 V,	Other inputs at V_{CC} or GND	3 V to 3.6 V			750	µA
C_i	Control inputs	V_I = V_{CC} or GND		3.3 V		3.5		pF
	Data inputs	V_I = V_{CC} or GND		3.3 V		6		pF
C_o	Outputs	V_I = V_{CC} or GND		3.3 V		7		pF

† For conditions shown as MIN or MAX, use the appropriate values under recommended operating conditions.
‡ All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

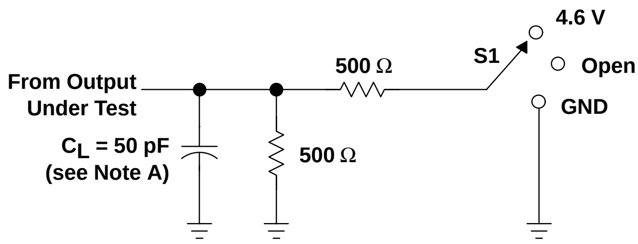
switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 2.5 V ± 0.2 V		V_{CC} = 2.7 V		V_{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
t_{pd}	A	Y	1.3	5.2		4.6	1.5	4	ns
t_{en}	$\overline{OE}$	Y	1.5	7		6.4	1.6	5.3	ns
t_{dis}	$\overline{OE}$	Y	2.4	6.3		5.4	1.8	4.9	ns

operating characteristics, T_A = 25°C

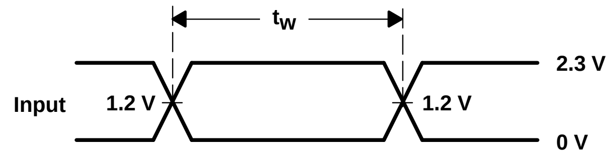
PARAMETER			TEST CONDITIONS	V_{CC} = 2.5 V ± 0.2 V	V_{CC} = 3.3 V ± 0.3 V	UNIT
				TYP	TYP	
C_{pd}	Power dissipation capacitance	Outputs enabled	C_L = 50 pF, f = 10 MHz	16	18	pF
		Outputs disabled		4	6	

PARAMETER MEASUREMENT INFORMATION
V_{CC} = 2.5 V ± 0.2 V

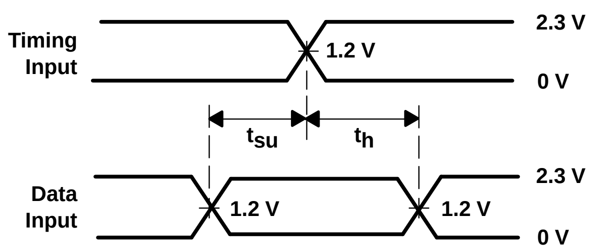


LOAD CIRCUIT

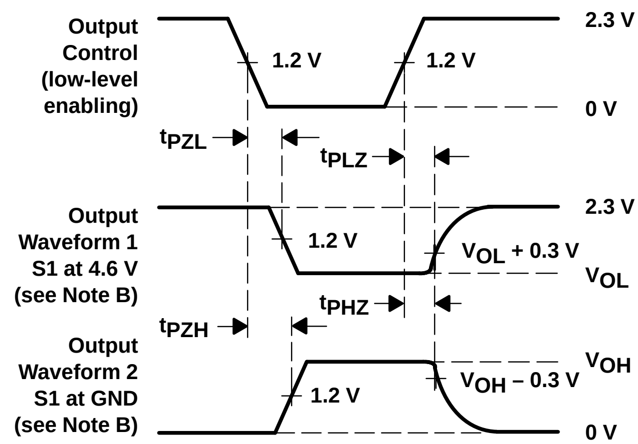
TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	4.6 V
t_{PHZ}/t_{PZH}	GND



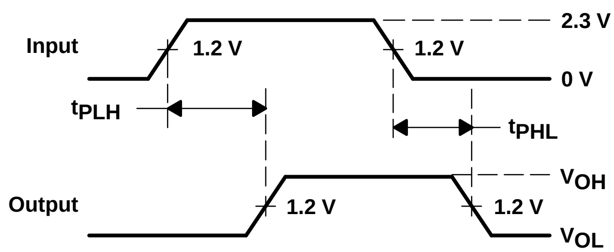
VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

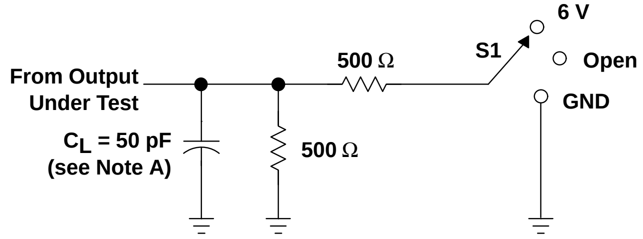


VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis}.
F. t_{PZL} and t_{PZH} are the same as t_{en}.
G. t_{PLH} and t_{PHL} are the same as t_{pd}.

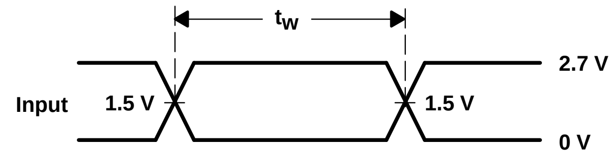
Figure 1. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION
V_{CC} = 2.7 V AND 3.3 V ± 0.3 V

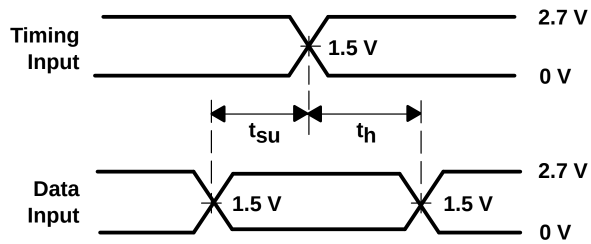


TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	6 V
t_{PHZ}/t_{PZH}	GND

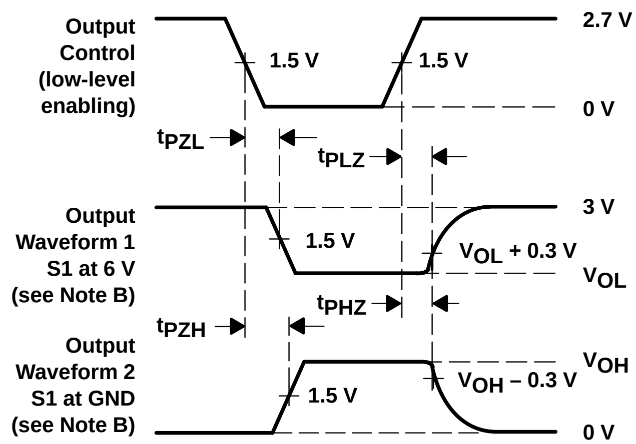
LOAD CIRCUIT

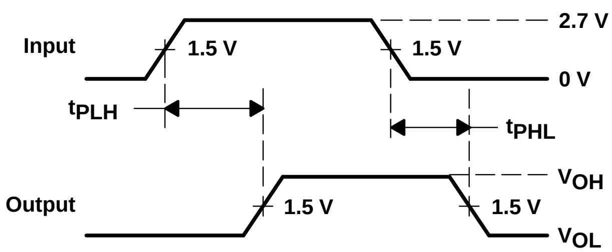


VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES





VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. t_{PLZ} and t_{PHZ} are the same as t_{dis}.
F. t_{PZL} and t_{PZH} are the same as t_{en}.
G. t_{PLH} and t_{PHL} are the same as t_{pd}.

Figure 2. Load Circuit and Voltage Waveforms

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